## Minghan Xian

List of Publications by Year in descending order

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759233 752698 28 413 12 20 h-index citations g-index papers 28 28 28 374 times ranked docs citations citing authors all docs

| #  | Article   | IF  | CITATIONS |
|----|---|-----|-----------|
| 1  | Vertical geometry 33.2 A, 4.8 MW cm2 Ga2O3 field-plated Schottky rectifier arrays. Applied Physics Letters, 2019, 114, .  | 3.3 | 50        |
| 2  | New methods for assessing electron storage capacity and redox reversibility of biochar. Chemosphere, 2019, 215, 827-834.  | 8.2 | 45        |
| 3  | Reverse Breakdown in Large Area, Field-Plated, Vertical β-Ga <sub>2</sub> O <sub>3</sub> Rectifiers. ECS<br>Journal of Solid State Science and Technology, 2019, 8, Q3159-Q3164.                                  | 1.8 | 36        |
| 4  | Demonstration of a SiC Protective Coating for Titanium Implants. Materials, 2020, 13, 3321.   | 2.9 | 24        |
| 5  | On the nature of photosensitivity gain in Ga2O3 Schottky diode detectors: Effects of hole trapping by deep acceptors. Journal of Alloys and Compounds, 2021, 879, 160394.   | 5.5 | 23        |
| 6  | Diffusion of implanted Ge and Sn in $\hat{I}^2$ -Ga2O3. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2019, 37, .   | 1.2 | 22        |
| 7  | Pulsed fast reactor neutron irradiation effects in Si doped n-type β-Ga <sub>2</sub> O <sub>3</sub> . Journal Physics D: Applied Physics, 2020, 53, 274001.   | 2.8 | 22        |
| 8  | Forward bias degradation and thermal simulations of vertical geometry $\hat{l}^2$ -Ga2O3 Schottky rectifiers. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2019, 37, .         | 1.2 | 17        |
| 9  | Effect of thermal annealing for W/l²-Ga2O3 Schottky diodes up to 600 °C. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2019, 37, .  | 1.2 | 17        |
| 10 | In Situ Observation of Î <sup>2</sup> -Ga <sub>2</sub> O <sub>3</sub> Schottky Diode Failure Under Forward Biasing Condition. IEEE Transactions on Electron Devices, 2020, 67, 3056-3061.                         | 3.0 | 16        |
| 11 | Role of hole trapping by deep acceptors in electron-beam-induced current measurements in β-Ga <sub>2</sub> O <sub>3</sub> vertical rectifiers. Journal Physics D: Applied Physics, 2020, 53, 495108.              | 2.8 | 16        |
| 12 | Fast SARS-CoV-2 virus detection using disposable cartridge strips and a semiconductor-based biosensor platform. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2021, 39, 033202. | 1.2 | 14        |
| 13 | Vertical $\hat{l}^2$ -Ga <sub>2</sub> O <sub>3</sub> Schottky rectifiers with 750 V reverse breakdown voltage at 600 K. Journal Physics D: Applied Physics, 2021, 54, 305103.                                     | 2.8 | 13        |
| 14 | Effect of Electron Injection on Minority Carrier Transport in 10 MeV Proton Irradiated β-Ga <sub>2</sub> O <sub>3</sub> Schottky Rectifiers. ECS Journal of Solid State Science and Technology, 2020, 9, 045018.  | 1.8 | 12        |
| 15 | Temperature dependent performance of ITO Schottky contacts on $\hat{I}^2$ -Ga2O3. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2021, 39, .   | 2.1 | 12        |
| 16 | Electron beam probing of non-equilibrium carrier dynamics in 18 MeV alpha particle- and 10 MeV proton-irradiated Si-doped <b> <i>î²</i> </b> -Ga2O3 Schottky rectifiers. Applied Physics Letters, 2021, 118, .    | 3.3 | 10        |
| 17 | Temperature dependence of cathodoluminescence emission in irradiated Si-doped $\hat{l}^2$ -Ga2O3. AIP Advances, 2021, 11, .   | 1.3 | 9         |
| 18 | Chemical methods for determining the electron storage capacity of black carbon. MethodsX, 2018, 5, 1515-1520.   | 1.6 | 8         |

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|----|--|------------|------------|
| 19 | Nitrogen ion-implanted resistive regions for edge termination of vertical Ga2O3 rectifiers. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2021, 39, 063405.  | 2.1        | 8          |
| 20 | Impact of electron injection on carrier transport and recombination in unintentionally doped GaN. Journal of Applied Physics, 2020, 128, .   | 2.5        | 7          |
| 21 | 1 GeV proton damage in β-Ga2O3. Journal of Applied Physics, 2021, 130, .   | 2.5        | 7          |
| 22 | In Situ Transmission Electron Microscopy Observations of Forward Bias Degradation of Vertical Geometry $\hat{l}^2$ -Ga <sub>2</sub> O <sub>3</sub> Rectifiers. ECS Journal of Solid State Science and Technology, 2020, 9, 055008. | 1.8        | 6          |
| 23 | Changes in band alignment during annealing at 600 °C of ALD Al2O3 on (InxGa1 â^' x)2O3 for xâd Journal of Applied Physics, 2020, 127, 105701.  | €‰=<br>2.5 | .0.25–0.74 |
| 24 | Rapid Electrochemical Detection for SARS-CoV-2 and Cardiac Troponin I Using Low-Cost, Disposable and Modular Biosensor System. , 2020, , .   |            | 5          |
| 25 | Annealing of Proton and Alpha Particle Damage in Au-W/ $\hat{l}^2$ -Ga2O3 Rectifiers. ECS Journal of Solid State Science and Technology, 2019, 8, P799-P804.   | 1.8        | 4          |
| 26 | Effects of Downstream Plasma Exposure on $\hat{l}^2$ -Ga <sub>2</sub> O <sub>3</sub> Rectifiers. ECS Journal of Solid State Science and Technology, 2021, 10, 065005.  | 1.8        | 4          |
| 27 | Annealing Effects on the Band Alignment of ALD SiO <sub>2</sub> on (In <sub>x</sub> Ga <sub>1â^'x</sub> ) <sub>2</sub> O <sub>3</sub> for x = 0.25â€"0.74. ECS Journal of Solid State Science and Technology, 2020, 9, 045001.     | 1.8        | 0          |
| 28 | Thermal effects in Ga2O3 rectifiers and MOSFETs borrowing from GaN., 2022,, 441-467.   |            | 0          |